Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
09/727,841	BUONANNO ET AL.		
Examiner	Art Unit		
Dienane M. Bayard	2141		

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Class	Subclass	Date	Examiner
709	227	4/14/2006	DB
709	238	4/14/2006	DB
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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